

PRODUCT/PROCESS CHANGE NOTIFICATION

PCN IPG-DIS/14/8497 Dated 29 May 2014

Assembly and testing transfer from ST China plant to subcontractor in China and ECOPACK2 conversion and leadframe rationalization

Table 1. Change Implementation Schedule

| Forecasted implementation date for change | 22-May-2014 |
|--|-------------|
| Forecasted availability date of samples for customer | 10-Jun-2014 |
| Forecasted date for STMicroelectronics change Qualification Plan results availability | 22-May-2014 |
| Estimated date of changed product first shipment | 28-Aug-2014 |

Table 2. Change Identification

| Product Identification (Product Family/Commercial Product) | AC Switches | | | |
|---|--|--|--|--|
| Type of change | Package assembly location change | | | |
| Reason for change | To optimize our industrial capacity | | | |
| Description of the change | see attached | | | |
| Change Product Identification | marking, internal codification and QA number | | | |
| Manufacturing Location(s) | | | | |

| Table 3. List of Attachmen | ıts |
|----------------------------|-----|
|----------------------------|-----|

| Customer Part numbers list | |
|----------------------------|--|
| Qualification Plan results | |

| Customer Acknowledgement of Receipt | PCN IPG-DIS/14/8497 |
|---|---------------------|
| Please sign and return to STMicroelectronics Sales Office | Dated 29 May 2014 |
| □ Qualification Plan Denied | Name: |
| □ Qualification Plan Approved | Title: |
| | Company: |
| □ Change Denied | Date: |
| □ Change Approved | Signature: |
| Remark | |
| | |
| | |
| | |
| | |
| | |
| | |
| | |
| | |
| 1 | |

47/.

DOCUMENT APPROVAL

| Name | Function |
|----------------|-------------------|
| Paris, Eric | Marketing Manager |
| Duclos, Franck | Product Manager |
| Cazaubon, Guy | Q.A. Manager |

A7/.



(1) IPG: Industrial & Power Group - ASD: Application Specific Device – IPAD™: Integrated Passive and Active Devices

PCN Product/Process Change Notification

AC Switches

Change 1: Assembly and testing transfer from ST China plant to subcontractor in China

| Change | ersion and leadframe | rationalization | |
|-------------------------|----------------------|---|--|
| Notification number: | IPG-DIS/14/8497 | Issue Date | 22/05/2014 |
| Issued by | Aline AUGIS | | I |
| Product series affected | by the change | <u>DPAK</u> | <u>IPAK</u> |
| | | ACST410-8B ACST410-8BTR ACST435-8B ACST435-8BTR FLC01-200B-TR FLC10-200B LIC01-215B-TR T405-600B T405-600B-TR T405-700B-TR T405-800B-TR T405-800B-TR T405-800B-TR T410-600B T410-600B-TR T410-800B-TR T410-800B-TR T435-600B T435-600B-TR T435-800B-TR T835-800B-TR T810-800B-TR T810-800B-TR T810-800B-TR T810-800B-TR T810-800B-TR T810-800B-TR T810-800B-TR T810-800B-TR T810-800B-TR T815-800B-TR T815-800B-TR TN1205T-600B TN1205T-600B TN1205T-600B-TR TN1215-600B-TR TN1215-600B-TR TN1215-600B-TR TN1215-800B-TR TN1515-600B-TR TN1515-600B-TR TN815-9BAS TN815-9BAS TN815-9BAS TN815-9BAS TN815-9BAS-TR TN815-9BAS TN815-9BAS-TR | FLC01-200H FLC01-200HEL LIC01-215H T405-600H T405-800H T410-600H T410-800H T435-800H T435-800H T35-600H TC05A6I TN1215-600H TN1215-800H TN815-800H TS1220-600H TS420-600H TS420-600H |

22-05-2014 1/3 Issue date

STMicroelectronics IPG - ASD & IPAD™ Division¹ BU Thyristors and Triacs



(1) IPG: Industrial & Power Group - ASD: Application Specific Device – IPAD™: Integrated Passive and Active Devices

| Type of change | Additional assembly package location |
|----------------|--------------------------------------|
| | |

Description of the change

| | Before | | | | After | | | | | |
|--------------------------|--------------|-------|---------|---------|-----------|--------------|-------|---------|---------|-----------|
| | | В | ack-End | | Farmark 2 | | В | ack-End | | Francis 2 |
| | Name | Туре | Country | Marking | Ecopack 2 | Name | Туре | Country | Marking | Ecopack 2 |
| DDAK | LGG | subco | China | G4 | N | | | | | |
| DPAK Thyristors & | STS | ST | China | GK | N | NFME- | subco | China | | v |
| Triacs | NFME- STD | subco | China | GF | N | Matrix | Subco | Cillia | GF | ' |
| IPAK Thyristors & Triacs | LGG | ST | China | G4 | N | NFME- STD | subco | China | GF | Υ |

Reason for change

Change 1: The change is performed in order to optimize our industrial capacity.

<u>Change 2:</u> ST upgrades its AC Switches housed in DPAK and IPAK packages with frame matrix and ECOPACK2 conversion in order to optimize its industrial process and give a better service to customers.

| Former versus changed product: | The changed products do not present modified electrical, parameters, leaving unchanged the current information published in the product datasheet, except for the POA. |
|--------------------------------|--|
| | The Moisture Sensitivity Level of the part (according to the IPC/JEDEC JSTD-020D standard) remains unchanged. |
| | The footprint recommended by ST remains the same. |
| | There is no change in the packing modes and the standard delivery quantities either. |
| | The products are now in full compliance with the ST ECOPACK®2 grade ("halogen-free"). |

Disposition of former products

Deliveries of former product will continue while the transfer is brought to completion and as long as former product stocks last.

Marking and traceability

Traceability for the implemented change will be ensured by the **marking**, an **internal codification** and by the **Q.A. number**.

For **ECOPACK2** conversion a letter "G" printed to the right of the "e3" symbol on the marking.

| Qualification complete date | 19-05-2014 |
|-----------------------------|------------|
| | |

Issue date 22-05-2014 2/3

STMicroelectronics IPG - ASD & IPAD™ Division¹ BU Thyristors and Triacs



(1) IPG: Industrial & Power Group - ASD: Application Specific Device – IPAD™: Integrated Passive and Active Devices

| Product family | Sub-family | Commercial part Number | Availability date |
|----------------|------------|---|-------------------|
| | | T405Q-600B-TR | |
| | | T405-600B-TR T410-600B-TR T435-700B-TR Week 24-2014 | |
| | | | |
| AO Omitakaa | Triacs | | Week 24-2014 |
| AC Switches | 111000 | TN815-800B-TR | Week 24-2014 |
| | | TS420-600B-TR | |
| | | T835-600B-TR | |
| | | TS820-800B-TR | |

Change implementation schedule

| Sales types | Estimated production start | Estimated first shipments |
|-------------|----------------------------|---------------------------|
| All | Week 21 - 2014 | Week 34 - 2014 |

Comments:

Customer's feedback

Please contact your local ST sales representative or quality contact for requests concerning this change notification.

Absence of acknowledgement of this PCN within 30 days of receipt will constitute acceptance of the change Absence of additional response within 90 days of receipt of this PCN will constitute acceptance of the change

| Qualification program and results QRP14097 |
|--|
|--|

Issue date 22-05-2014 3/3



External Reliability Report

Qualification of DPAK/IPAK package at china subcontractor

| Gener | al Information | Loca | Locations | | |
|----------------------|---------------------|------------------------|-------------------------------|--|--|
| Product Lines | AC Switches | Wafer fab | STMicroelectronics Tours | | |
| Products Description | ACS/TRIAC/Thyristor | Assembly plant | China Subcontractor (998G) | | |
| Product Group | IPG | Reliability Lab | STMicroelectronics Tours | | |
| Product division | ASD&IPAD | Reliability assessment | Passed | | |
| Package | DPAK/IPAK | | | | |

DOCUMENT INFORMATION

| Version | Date | Pages | Prepared by | Approved by | Comment |
|---------|------|-------|------------------|--------------------|-------------|
| Rev. 1 | May | 14 | Gilles DUTRANNOY | Jean-Paul REBRASSE | First issue |

Note: This report is a summary of the reliability trials performed in good faith by STMicroelectronics in order to evaluate the potential reliability risks during the product life using a set of defined test methods.

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IPG (Industrial & Power Group) ASD & IPAD division Quality and Reliability

May 15, 2014 Report ID: 14097

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1 APPLICABLE AND REFERENCE DOCUMENTS

| Document reference | Short description | |
|--------------------|---|--|
| JESD 47 | Stress-Test-Driven Qualification of Integrated Circuits | |
| MIL-STD-750C | Test method for semiconductor devices | |
| SOP 2614 | Reliability requirements for product qualification (ST internal document) | |
| SOP 267 | Product maturity levels (ST internal document) | |
| 0061692 | Reliability tests and criteria for qualifications (ST internal document) | |

2 GLOSSARY

| BOM | Bill Of Materials | |
|------|-------------------------------|--|
| DUT | Device Under Test | |
| F/G | Finished Good | |
| HTRB | High Temperature Reverse Bias | |
| PCT | Pressure Cooker Test | |
| P/N | Part Number | |
| RH | Relative Humidity | |
| SS | Sample Size | |
| TCT | Temperature Cycling Test | |
| THB | Temperature Humidity Bias | |

IPG (Industrial & Power Group) ASD & IPAD division Quality and Reliability

May 15, 2014 Report ID: 14097

3 RELIABILITY EVALUATION OVERVIEW

3.1 Objectives

Qualification of DPAK/IPAK package at china subcontractor.

3.2 Conclusion

Qualification Plan requirements have been fulfilled without exception. Reliability tests have shown that the devices behave correctly against environmental tests (no failure). Moreover, the stability of electrical parameters during the accelerated tests demonstrates the robustness of the product which is consequently expected during their lifetime



Devices Characteristics

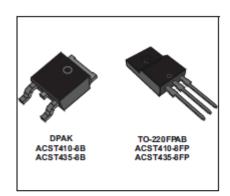
3.3 **Devices description**



ACST4

Overvoltage protected AC switch

Datasheet - production data



Features

- · Triac with overvoltage protection
- Low I_{GT} (<10 mA) or high immunity (I_{GT}<35 mA) version
- High noise immunity: static dV/dt > 1000 V/µs
- · TO-220FPAB insulated package: 1500 V rms

- Enables equipment to meet IEC 61000-4-5
- · High off-state reliability with planar technology
- · Needs no external overvoltage protection
- · Reduces the power passive component count
- · High immunity against fast transients described in IEC 61000-4-4 standards

Applications

- · AC mains static switching in appliance and industrial control systems
- Drive of medium power AC loads such as:
 - Universal motor of washing machine drum
 - Compressor for fridge or air conditioner

Description

The ACST4 series belongs to the ACS™/ACST power switch family. This high performance device is suited to home appliances or industrial systems and drives loads up to 4A.

This ACST4 switch embeds a Triac structure with a high voltage clamping device to absorb the inductive turn-off energy and withstand line transients such as those described in the IEC 61000-4-5 standards. The ACST410 needs a low gate current to be activated (I_{GT} < 10 mA) and still shows a high electrical noise immunity complying with IEC standards such as IEC 61000-4-4 (fast transient burst test).

Figure 1. Functional diagram

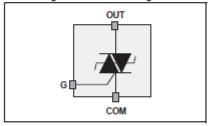


Table 1. Device summary

| Symbol | Value | Unit |
|------------------------------------|-------|------|
| I _{T(RMS)} | 4 | Α |
| V _{DRM} /V _{RRM} | 800 | V |
| I _{GT} (ACST410) | 10 | mA |
| I _{GT} (ACST435) | 35 | mA |

TM: ACS is a trademark of STMicroelectronics

DocID8766 Rev 6

May 2014 This is information on a product in full production.

1/14

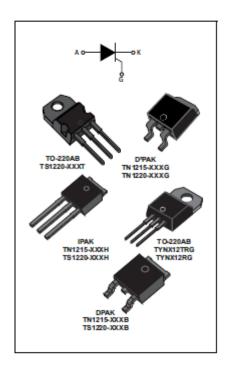




TN12_TS12_TYNX12

Sensitive and standard 12 A SCRs

Datasheet - production data



Features

- On-state rms current, I_{T(RMS)} 12A
- Repetitive peak off-state voltage, V_{DRM}/V_{RRM} 600 and 1000 V
- Triggering gate current, I_{GT} 0.2 to 15 mA

Description

Available either in sensitive (TS1220) or standard (TN1215 / TYNX12) gate triggering levels, the 12A SCR series is suitable to fit all modes of control, found in applications such as overvoltage crowbar protection, motor control circuits in power tools and kitchen aids, inrush current limiting circuits, capacitive discharge ignition and voltage regulation circuits.

Available in through-hole or surface-mount packages, they provide an optimized performance in a limited space.

Table 1. Device summary

| Order | Voltage (x00) V _{DRM} /V _{RRM} | | Іот | Package | | |
|-----------------|---|-----|-----|---------|--------|--------------------|
| code | 600 | 700 | 800 | 1000 | | |
| TN1215 -xxxB | х | | х | | 15 mA | DPAK |
| TN1215 -xxxG | x | | х | | 15 mA | D ² PAK |
| TN1215 -xxxH | x | | x | | 15 mA | IPAK |
| TS1220 -xxxB | x | х | | | 0.2 mA | DPAK |
| TS1220 -xxxH | x | | | | 0.2 mA | IPAK |
| TS1220 -xxxT | x | | | | 0.2 mA | TO-220AB |
| TYNx12 RG | x | | х | х | 15 mA | TO-220AB |
| TYNx12 TRG | x | | x | х | 5 mA | TO-220AB |

May 2014 DoolD7475 Rev 8 1/18

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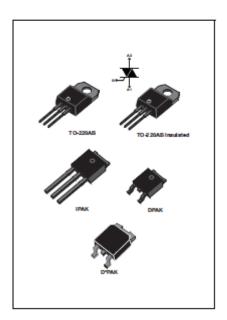




BTA08, BTB08 and T8 Series

Snubberless™, logic level and standard 8 A Triacs

Datasheet - production data



Description

Available either in through-hole or surface-mount packages, the BTA08, BTB08 and T8 Triac series is suitable for general purpose AC switching. They can be used as an ON/OFF function in applications such as static relays, heating regulation, induction motor starting circuits... or for phase control operation in light dimmers, motor speed controllers....

The Snubberless versions (BTA/BTB...W and T8 series) are specially recommended for use on inductive loads, thanks to their high commutation performances.

Logic level versions are designed to interface directly with low power drivers such as microcontroller.

By using an internal ceramic pad, the BTA series provides voltage insulated tab (rated at 2500 VRMS) complying with UL standards (file ref.: E81734).

Features

- On-state rms current, I_{T(RMS)} 8 A
- Repetitive peak off-state voltage, V_{DRM}/V_{RRM} 600 to 800 V
- Triggering gate current, I_{GT (Q1)} 5 to 50 mA

May 2014 DoolD7472 Rev 8 1/18

This is information on a product in full production.

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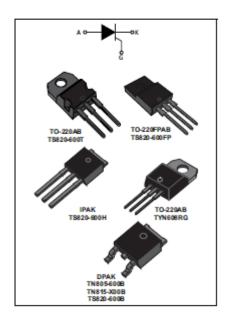




TN805, TN815, TS820, TYN608

Sensitive and standard 8 A SCRs

Datasheet - production data



Features

- On-state rms current, I_{T(RMS)} 8 A
- Repetitive peak off-state voltage, V_{DRM}/V_{RRM} 600 and 800 V
- Triggering gate current, I_{GT} 0.2 to 15 mA

Description

Available either in sensitive (TS8) or standard (TN8 / TYN) gate triggering levels, the 8 A SCR series is suitable to fit all modes of control found in applications such as overvoltage crowbar protection, motor control circuits in power tools and kitchen aids, inrush current limiting circuits, capacitive discharge ignition and voltage regulation circuits.

Available in through-hole or surface-mount packages, they provide an optimized performance in a limited space.

Table 1. Device summary

| Order code | Voltag V _{DRM} | e (x00) /V _{RRM} | Sensitivity | Package | |
|-------------|----------------------------|------------------------------|-------------|--------------------|--|
| | 600 V | 800 V | ат | | |
| TS820-600B | X | | 0.2 mA | DPAK | |
| TS820-600H | X | | 0.2 mA | IPAK | |
| TS820-600T | X | | 0.2 mA | TO- 220AB | |
| TS820-600FP | x | | 0.2 mA | TO- 220FPA B | |
| TN805-600B | X | | 5 mA | DPAK | |
| TN815-x00B | Х | Х | 15 mA | DPAK | |
| TYN608RG | x | | 15 mA | TO- 220AB | |

May 2014 DocID7476 Rev 8 1/17

This is information on a product in full production.



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4 TESTS RESULTS SUMMARY

4.1 Test vehicles

5 test vehicles were chosen:

- T835-600B-TR assembled in DPAK package
- ACST410-8BTR assembled in DPAK package
- TN1215-800B-TR assembled in DPAK package
- T835-600H assembled in IPACK package
- TS820-600H assembled in IPACK package

| Lot # | Part number | Process/ Package | Comments |
|-------|----------------|------------------|---------------|
| L1 | T835-600B-TR | DPAK | Qualification |
| L2 | ACST410-8BTR | DPAK | lot |
| L3 | TN1215-800B-TR | DPAK | |
| | | | |
| L4 | T835-600H | IPAK | Qualification |
| L5 | TS820-600H | IPAK | lot |

The results are detailed in the next sections.

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4.2 Test plan and results summary

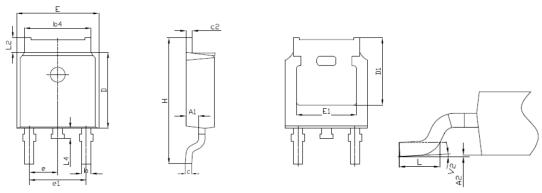
| Test | PC Std ref. | Conditions | cc | Stone | Failure/SS | | | | Nata | | |
|------|-------------|--|-------------------------------------|--------|---------------|-------|-------|-------|-------|-------|------|
| rest | | Sta ref. | Conditions | SS | Steps | Lot 1 | Lot 2 | Lot 3 | Lot 4 | Lot 5 | Note |
| | | JESD22 A- 108 | 108 $T_j = 125 \text{ °C}$ VAC 750C | 385 | 168 h | 0/77 | 0/77 | 0/77 | 0/77 | 0/77 | |
| HTRB | N | | | | 500 h | 0/77 | 0/77 | 0/77 | 0/77 | 0/77 | |
| | | method | | | 1000 h | | | | | | |
| | | Y JESD22 A- 101 85 °C 85% RH V _r = 100 V | | 125 | 168 h | 0/25 | 0/25 | 0/25 | 0/25 | 0/25 | |
| тнв | Y | | 85% RH | | 500 h | 0/25 | 0/25 | 0/25 | 0/25 | 0/25 | |
| | | | | 1000 h | | | | | | | |
| PCT | Υ | JESD22 A-102 | 121°C 2bar 100% RH | 125 | 96 h | 0/25 | 0/25 | 0/25 | 0/25 | 0/25 | |
| тс | Υ | JESD22 A- 104 | -65 °C/+150 °C 2 cycles/h | 125 | 500 cycles | 0/25 | 0/25 | 0/25 | 0/25 | 0/25 | |
| RSH | N | JESD22 B- 106-A | 260°C 10S 2 immersions | 60 | 2 dipping | 0/12 | 0/12 | 0/12 | 0/12 | 0/12 | |



5 ANNEXES

5.1 <u>Device details</u>

5.1.1 Package outline/Mechanical data for DPAK



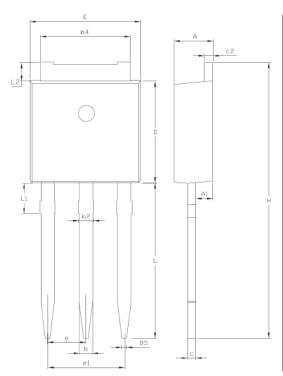
DIMENSIONS FOR TYPE "H"

| ASE - NFME – SUBCON. | | | | | |
|----------------------|-----|-------|-------|--|--|
| REF.DIM | DA | NOTES | | | |
| | NOM | MIN | MAX | | |
| A | | 2.18 | 2.40 | | |
| A1 | | 0.9 | 1.10 | | |
| A2 | | 0.03 | 0.23 | | |
| b | | 0.64 | 0.90 | | |
| b4 | | 4.95 | 5.46 | | |
| c | | 0.46 | 0.61 | | |
| c2 | | 0.46 | 0.60 | | |
| D | | 5.97 | 6.22 | | |
| D1 | | 5.1 | | | |
| E | | 6.35 | 6.73 | | |
| E1 | | 4.32 | | | |
| e1 | | 4.4 | 4.7 | | |
| H | | 9.35 | 10.40 | | |
| L | | 1.0 | 1.78 | | |
| L2 | | | 1.27 | | |
| L4 | | 0.6 | 1.02 | | |
| V2 | | 0° | 8° | | |
| | | | | | |
| | | | | | |





5.1.2 Package outline/Mechanical data for IPAK



| | DIME | NSIONS FO | R TYPE "D | " |
|---------|-------|-----------|-----------|----|
| | C | OMMON N | FME - ST | |
| REF.DIM | DA | TA BOOK | NOTES | |
| KET.DIM | NOM | MIN | MAX | 2 |
| A | | 2.20 | 2.40 | |
| Al | | 0.90 | 1.10 | ,0 |
| ь | | 0.64 | 0.90 | 27 |
| b2 | | | 0.95 | ~ |
| b4 | | 5.20 | 5.43 | |
| B5 | 0.30 | | 0 | |
| c | | 0.45 | 0.60 | |
| c2 | | 0.46 | 0.60 | |
| D | | 6.00 | 6.20 | |
| E | | 6.40 | 6.70 | |
| e | 2.28 | | | |
| el | | 4.40 | 4.60 | |
| H | 16.10 | 8 | | |
| L | 4 | 9.00 | 9.60 | |
| Ll | 4 | 0.80 | 1.20 | |
| L2 | 0.80 | | 1.25 | |
| Vl | 910° | | | |
| | / | | | |

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5.2 <u>Tests Description</u>

| Test name | Description | Purpose | | |
|--|--|--|--|--|
| | Die-oriented test | | | |
| HTRB (AC mode) High Temperature Reverse Bias | The device is stressed here in AC mode, trying to satisfy as much as possible the following conditions: - Low power dissipation. - Peak supply voltage compatible with diffusion process and internal circuitry limitations. | To determine the effects of bias conditions and temperature on solid state devices over time. It simulates the devices operating condition in an accelerated way. To maximize the electrical field across either reverse-biased junctions or dielectric layers, in order to investigate the failure modes linked to mobile contamination, oxide aging, layout sensitivity to surface effects. | | |
| | Die and Package-orient | | | |
| THB Temperature Humidity Bias | The device is biased in static configuration minimizing its internal power dissipation, and stored at controlled conditions of ambient temperature, and relative humidity. | To evaluate the package moisture resistance with electrical field applied, both electrolytic and galvanic corrosion are put in evidence. | | |
| TC Temperature Cycling | The device is submitted to cycled temperature excursions, between a hot and a cold chamber in air atmosphere. | To investigate failure modes related to the thermo-mechanical stress induced by the different thermal expansion of the materials interacting in the die-package system. Typical failure modes are linked to metal displacement, dielectric cracking, molding compound delamination, wire-bonds failure, die-attach layer degradation. | | |
| RSH | Device is submitted to a dipping in a solder bath at 260°C with a dwell time of 10s. Only for through hole mounted devices. | This test is used to determine whether solid state devices can withstand the effects of the temperature to which they will be subjected during soldering of their leads. The heat is conducted through the leads into the device package from solder heat at the reverse side of the board. This procedure does not simulate wave soldering or reflow heat exposure on the same side of the board as the package body. | | |
| PCT Pressure Cooker Test | The device is unbiased under 121 °C, and a 2 bars air atmosphere during 96 hours. | The PCT is performed to evaluate the reliability of non-hermetic packaged solid-state devices in humid environments. It employs severe conditions of temperature, humidity, and pressure which accelerate the penetration of moisture through the external protective material (encapsulant or seal) or along the interface between the external protective material and the metallic conductors which pass through it. The stress usually activates the same failure mechanisms as the "85/85" Steady-State Humidity Life Test (THB). | | |



IPG (Industrial & Power Group) ASD & IPAD division Quality and Reliability

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AppendixList of product involved in this qualification

| ср | pkdescr |
|---------------|-------------|
| ACST410-8B | TO 252 DPAK |
| ACST410-8BTR | TO 252 DPAK |
| ACST435-8B | TO 252 DPAK |
| ACST435-8BTR | TO 252 DPAK |
| FLC01-200B-TR | TO 252 DPAK |
| FLC01-200H | IPAK TO-251 |
| FLC01-200HEL | IPAK TO-251 |
| FLC10-200B | TO 252 DPAK |
| LIC01-215B-TR | TO 252 DPAK |
| LIC01-215H | IPAK TO-251 |
| T405-600B | TO 252 DPAK |
| T405-600B-TR | TO 252 DPAK |
| T405-600H | IPAK TO-251 |
| T405-700B-TR | TO 252 DPAK |
| T405-800B-TR | TO 252 DPAK |
| T405-800H | IPAK TO-251 |
| T405Q-600B-TR | TO 252 DPAK |
| T405Q-600H | IPAK TO-251 |
| T410-600B | TO 252 DPAK |
| T410-600B-TR | TO 252 DPAK |
| T410-600H | IPAK TO-251 |
| TS820-600H | IPAK TO-251 |

| ср | pkdescr |
|-----------------|-------------|
| T410-800B-TR | TO 252 DPAK |
| T410-800H | IPAK TO-251 |
| T435-600B | TO 252 DPAK |
| T435-600B-TR | TO 252 DPAK |
| T435-600H | IPAK TO-251 |
| T435-700B-TR | TO 252 DPAK |
| T435-800B-TR | TO 252 DPAK |
| T435-800H | IPAK TO-251 |
| T810-600B | TO 252 DPAK |
| T810-600B-TR | TO 252 DPAK |
| T810-800B-TR | TO 252 DPAK |
| T835-600B | TO 252 DPAK |
| T835-600B-TR | TO 252 DPAK |
| T835-600H | IPAK TO-251 |
| T835-800B | TO 252 DPAK |
| T835-800B-TR | TO 252 DPAK |
| TC05A6I | IPAK TO-251 |
| TN1205T-600B | TO 252 DPAK |
| TN1205T-600B-TR | TO 252 DPAK |
| TN1215-600B | TO 252 DPAK |
| TN1215-600B-TR | TO 252 DPAK |
| TS820-700B-TR | TO 252 DPAK |

| ср | pkdescr |
|----------------|-------------|
| TN1215-600H | IPAK TO-251 |
| TN1215-800B-TR | TO 252 DPAK |
| TN1215-800H | IPAK TO-251 |
| TN1515-600B-TR | TO 252 DPAK |
| TN805-600B-TR | TO 252 DPAK |
| TN815-600B-TR | TO 252 DPAK |
| TN815-800B-TR | TO 252 DPAK |
| TN815-800H | IPAK TO-251 |
| TN815-9BAS | TO 252 DPAK |
| TN815-9BAS-TR | TO 252 DPAK |
| TS1220-600B | TO 252 DPAK |
| TS1220-600B-TR | TO 252 DPAK |
| TS1220-600H | IPAK TO-251 |
| TS410-600BCTR | TO 252 DPAK |
| TS420-600B | TO 252 DPAK |
| TS420-600BCTR | TO 252 DPAK |
| TS420-600B-TR | TO 252 DPAK |
| TS420-600H | IPAK TO-251 |
| TS450-600BCTR | TO 252 DPAK |
| TS820-600B | TO 252 DPAK |
| TS820-600B-TR | TO 252 DPAK |
| TS820-800BM-TR | TO 252 DPAK |

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